CONTENTS

Preface *ix*
Acknowledgments *xiii*

Chapter 1. **An Introduction to Optical Multiplexing Techniques** 1

1.1 Introduction 1
1.2 Weighing designs and optical multiplexing 6
1.3 Masks from Hadamard matrices and *S*-matrices 12

Chapter 2. **A Survey of Multiplexing Spectrometers** 20

2.1 Introduction 20
2.2 Spectrometers which use interference methods 24
2.3 Spectrometers which use masks 29
2.4 A survey of multiplexing mask spectrometers 32
2.4.1 Simple masking spectrometer 32
2.4.2 Golay's static multislit spectrometer 33
2.4.3 Golay's dynamic multislit spectrometer 37
2.4.4 Girard's grill spectrometer 39
2.4.5 Mertz's mock interferometer 41
2.4.6 Hadamard transform spectrometers 43

Chapter 3. **The Basic Theory of Hadamard Transform Spectrometers and Imagers** 44

3.1 Introduction 44
3.1.1 Comparison of different encoding schemes 46
3.2 Analysis of a singly encoded spectrometer 46
3.2.1 The basic equation relating measurements and unknowns 47
3.2.2 Estimating the spectrum 50

3.2.3 The mean square error of the estimates 51
3.2.4 Hotelling's bound on the mean square error 54
3.2.5 Masks with the largest determinant 56
3.2.6 Masks of 0's and 1's; S-matrices 57
3.2.7 Cyclic masks 61
3.3 Imagers 62
3.3.1 Definition of an imager 63
3.3.2 Hadamard transform imager 63
3.3.3 Folding the mask configuration 65
3.4 Doubly encoded spectrometers and imaging spectrometers 70
3.4.1 Imaging spectrometer 70
3.4.2 The S-matrix grill spectrometer 74
3.4.3 A second doubly encoded spectrometer 78
3.4.4 If *mn* measurements are made 80
3.5 More measurements than unknowns; generalized inverses 82
3.5.1 Moore–Penrose generalized inverse 82
3.5.2 Singly multiplexed spectrometer 83
3.5.3 Doubly multiplexed instrument 84
3.5.4 Realizing a Hadamard design with two detectors 85
3.6 Comparison with the Michelson interferometer 88
3.6.1 Comparison of singly encoded instruments 88
3.6.2 Comparison of doubly encoded spectrometers with wide aperture interferometers 92
3.6.3 Mertz's mock interferometer 92
3.6.4 Rotating grid collimator 94
3.6.5 Comparison of noise in different multiplexing methods 94

Chapter 4. **Noise, or When to Multiplex and When to Avoid it** 96

4.1 Observed gain in signal-to-noise ratio 96
4.2 Light losses 97
4.3 Sources of noise 99
4.4 Comparison of noise in different instruments 104

Chapter 5. **Instrumental Considerations** 109

5.1 Optics for singly encoded spectrometers 109
5.2 Pupils and stops 112
5.3 Diffraction 112
5.4 Aberrations 117
5.4.1 Spherical aberration 118
5.4.2 Coma 118
5.4.3 Distortion 120
5.4.4 Curvature of field 121
5.4.5 Astigmatism 121
5.4.6 Chromatic aberration 121
5.5 Image defects occurring in dispersive spectrometers 122
5.5.1 Curvature of slit image 123
5.5.2 Anamorphic magnification 128
5.6 Optical limitations in practice 129

5.7 Grating efficiency 131
5.8 Doubly encoded and imaging spectrometers 132
5.9 Operation of a doubly encoded spectrometer as an imaging spectrometer 135
5.10 Design of imaging spectrometers 136
5.11 Electronic system constraints 141
5.12 Light gathering power of Hadamard and Fourier transform spectrometers 143

Chapter 6. **Systematic Errors** 146

6.1 Introduction 146
6.2 Description of instrument and spectrum: simplest case 147
6.2.1 Description of instrument 147
6.2.2 Description of spectrum 149
6.2.3 Operation as a multiplexing spectrometer 151
6.2.4 Example 1: no diffraction 153
6.2.5 Example 2: full diffraction 154
6.2.6 Operation as a monochromator 156
6.2.7 Recovery of spectrum 156
6.2.8 Computing the spectrum. Inverse matrices 157
6.3 Errors occurring with a mask which is moved in steps 161
6.3.1 Faulty mask alignment 162
6.3.2 Differences between slit width and step size 163
6.3.3 Undercutting in the mask pattern 164
6.3.4 Excessive gap between encoding and blocking masks 165
6.3.5 Nonlinearities 166
6.4 Distortion introduced by a continuously moving mask 167
6.4.1 Derivation of basic equation 167
6.4.2 An ideal case 170
6.4.3 If the mask velocity or slit width is wrong 171
6.4.4 Rotating two-dimensional masks 172
6.4.5 Imaging a moving source 172
6.5 Effect of drift in background level 172
6.6 Singular designs 175
6.6.1 More measurements than unknowns 175
6.6.2 More unknowns than measurements 176
6.6.3 Correction procedures 177

Chapter 7. **Applications** 181

7.1 Chemical spectroscopy 181
7.2 Imaging spectrometry 182
7.3 Photoacoustic spectroscopy and imaging 187
7.4 Determining the sensitivity of color film 188
7.5 Arrays of detectors 189
7.6 Hadamard transforms in image processing 191
7.7 Astronomy 195
7.8 Medical applications 197
7.9 Miscellaneous applications 198

Appendix. **Hadamard and S-Matrices, Walsh Functions, Pseudo-Random Sequences, and the Fast Hadamard Transform** 200

A.1 Introduction 200
A.2 Construction of cyclic S-matrices 200
A.2.1 Definition of Hadamard and S-matrices 201
A.2.2 The quadratic residue construction of S-matrices 203
A.2.3 The construction of S-matrices using maximal length shift-register sequences 205
A.2.4 The twin prime construction for S-matrices 208
A.2.5 Other constructions of Hadamard matrices 210
A.3 Hadamard matrices and pseudo-random sequences 210
A.4 The relationship between Hadamard matrices and Walsh functions 212
A.5 Hadamard matrices and error-correcting codes 214
A.6 The fast Hadamard and Fourier transforms 214
A.6.1 A fast way to multiply by a Hadamard matrix 216
A.6.2 A fast way to multiply by S_n^{-1} 220
A.6.3 The fast Fourier transform 224

Bibliography 229
Index 245